



SPICE Model MA4P161-134

Nov 3, 2022





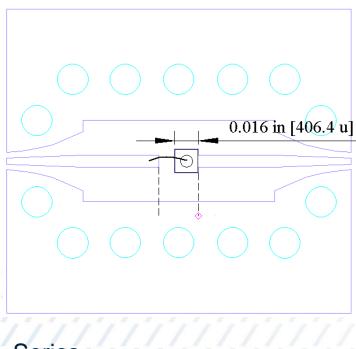
Contents

- Test Fixtures
- Bond Wire
- Diode
- Results
 - IV Curve
 - Series 100 mA
 - Series -40 V
 - Shunt 100 mA
 - Shunt -40 V
- Disclosure

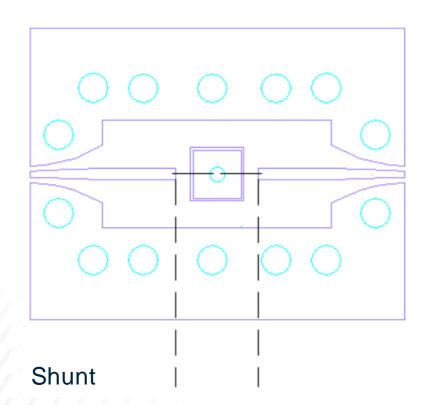


Test Fixtures

- 10 mils Rogers RO3010 with 1/2 oz copper
- S-parameters measured with port extensions such that the reference planes are set to the dash lines on the input and output as shown below

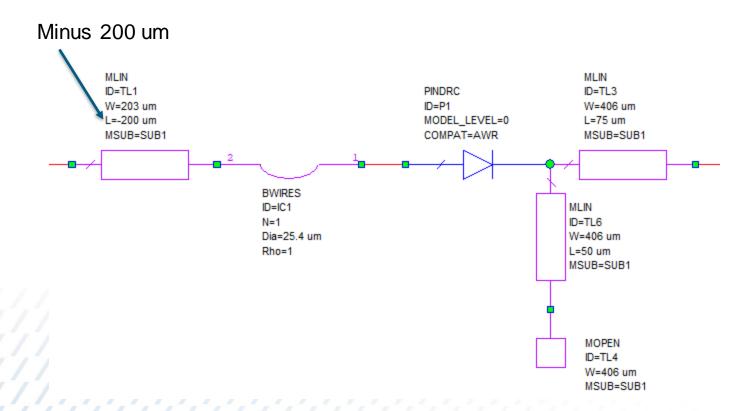


Series



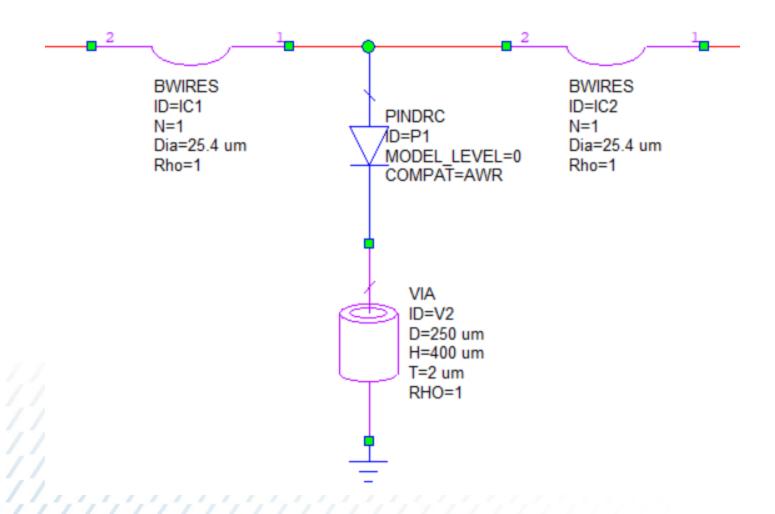


Series Test Fixture Model



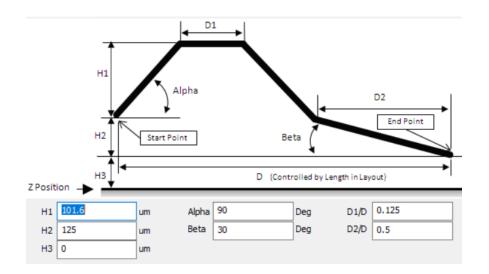


Shunt Test Fixture Model





Bond Wire



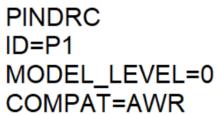
Element Options: BWIRES - Bond wire model (EIA/JEDEC Standard No. 59)

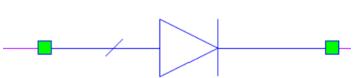
Bondwire Prof	ile Parameters	User At	tributes	Symbol	Layout	Mod	lel Optio
7 2 nd ₁	Yield # 5						
Name	Value	Unit	Tune	Optimize	Cons	train	Lower
ID	IC1						
N	1						
Dia	25.4	um					
Rho	1						
WModel	4 segments						
Alpha	90	Deg					
Beta	30	Deg					
H1	101.6	um					
H2	125	um					
H3	0	um					
D1_Ratio	0.125						
D2_Ratio	0.5						
P0	{0,0}	um					
P1	{BW_len,0}	um					
IndModel	RLC						

BW_len = 770



Robert Caverly PIN Diode Model



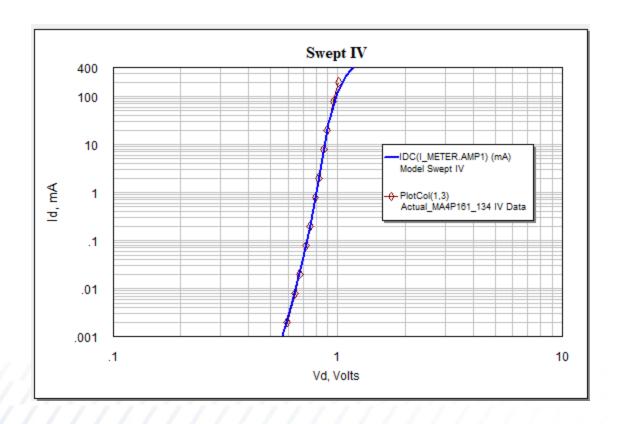


Name	Value	Unit	
ID	P1		
IS	Is	mA	
IKNEE	Iknee	mA	
N	Npin		
RLIM	Rs	Ohm	
REPI	Repi	Ohm	
CJ	Cj	pF	
CPKG	Cpkg	pF	
TAU	LT	ns	
W	W		
В	3		
LBOND	Lpkg	nH	
TNOM	26.85	DegC	
TEMP	26.85	DegC	
AREA	1		
NFLAG	Noise Off		

Is=1e-10 Iknee=2 Npin=0.68 Repi=1000 LT=150 W=13 Cj=0.055Rs=0.3 Cpkg=0 Lpkg=0

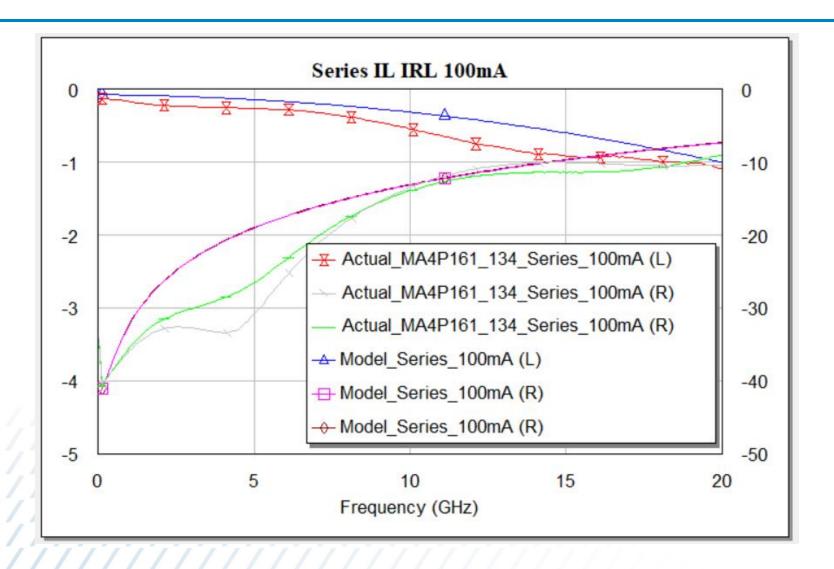


IV Curve



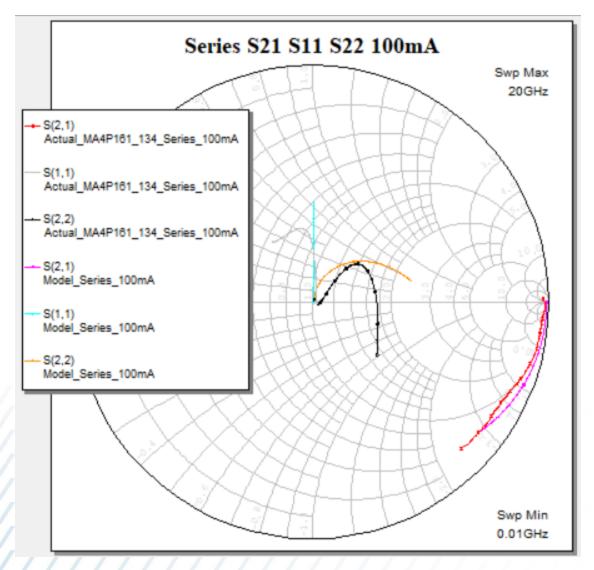


Series 100 mA



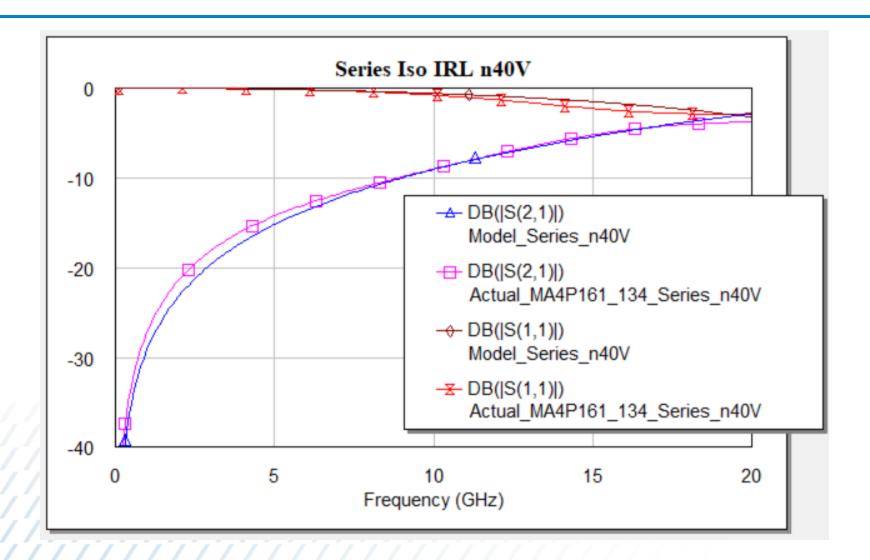


Series 100 mA



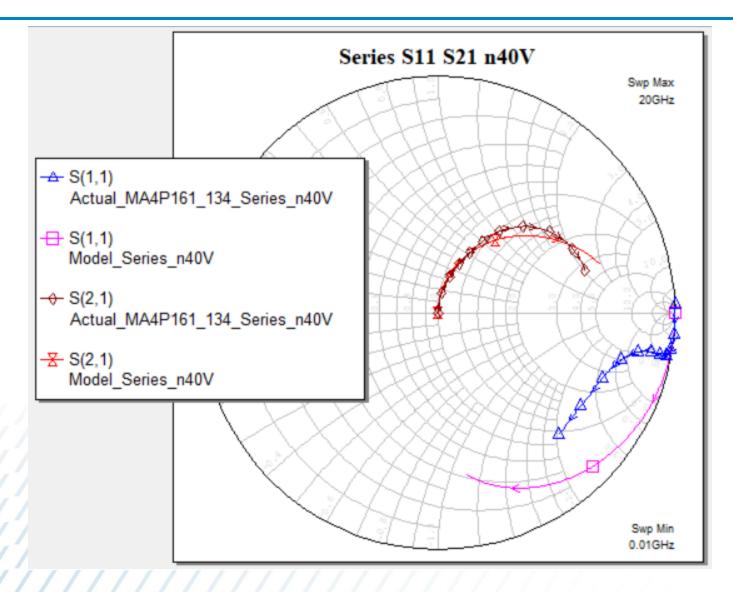


Series -40 V



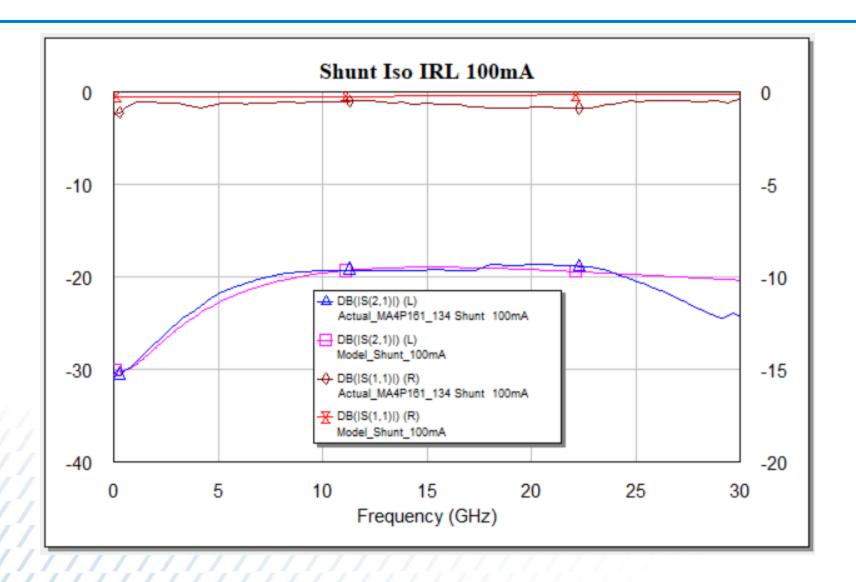


Series -40 V



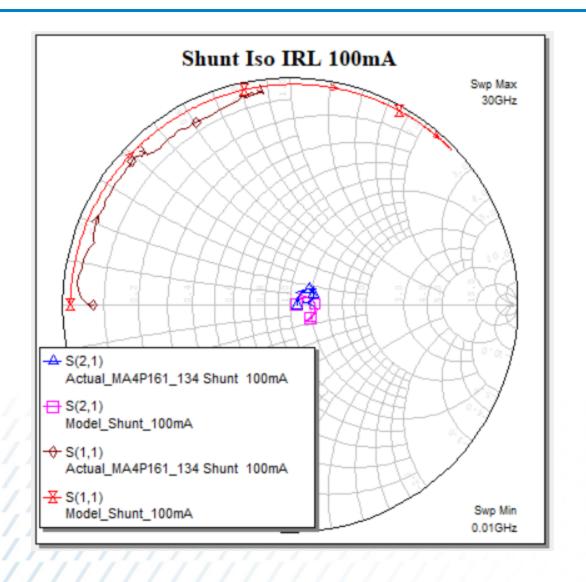
Shunt 100 mA





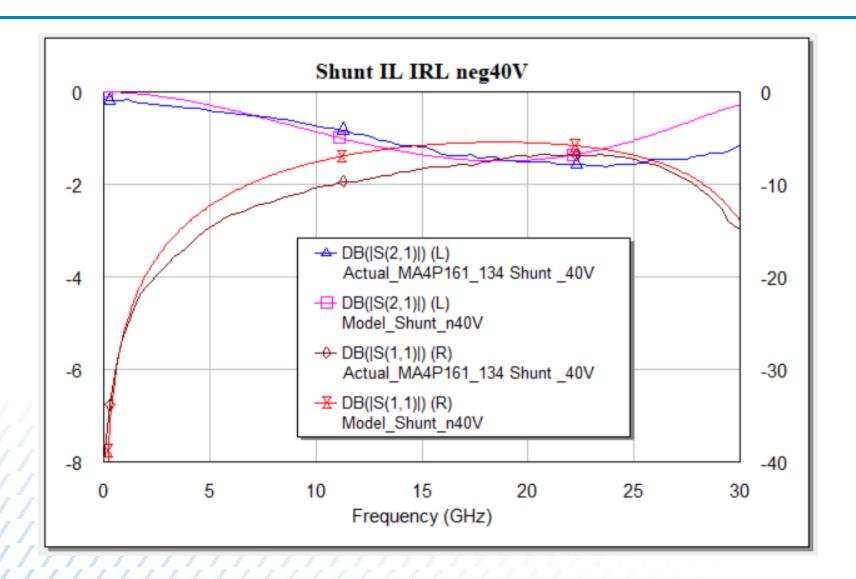
Shunt 100 mA





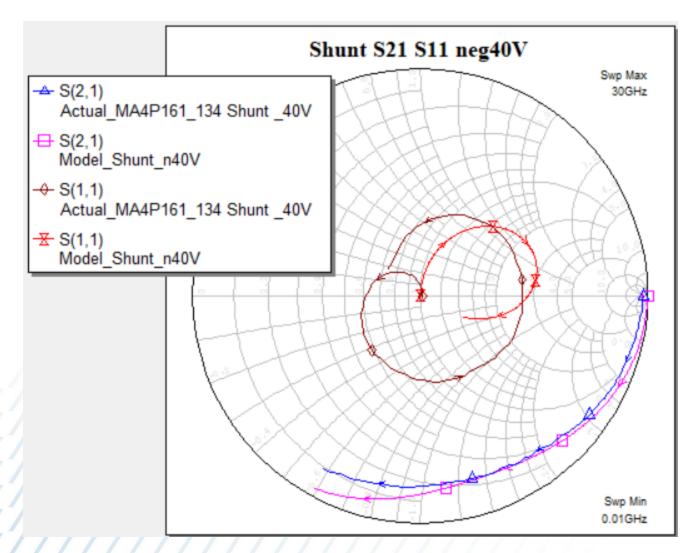
Shunt -40 V





Shunt -40 V Believe S11 Model over Measurement





Disclosure



These models are furnished on an "as is" basis without warranty of any kind. MACOM reserves the right to make changes to any model without notice. Although the use of models can be a useful tool in evaluating devices for applications, they do not exactly model all device characteristics under all conditions.